## Notice of References Cited Application/Control No. 10/797,581 Examiner Todd M. Epps Applicant(s)/Patent Under Reexamination BECK ET AL. Art Unit Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,615,428	09-2003	Pattee, Jeffrey Wayne	5/601
*	В	US-5,680,820	10-1997	Randolph, Travis M.	108/25
*	С	US-4,828,342	05-1989	Stefan, Alexander	312/223.3
*	D	US-5,450,800	09-1995	Leonard, Joseph W.	108/7
*	Е	US-5,408,940	04-1995	Winchell, Paul W.	108/147
*	F	US-5,398,622	03-1995	Lubinskas et al.	108/145
*	G	US-4,365,561	12-1982	Tellier et al.	108/7
*	Ι	US-4,669,789	06-1987	Pemberton, Peter F.	312/223.3
*	I	US-5,199,773	04-1993	Price et al.	312/7.2
*	J	US-6,736,469	05-2004	Long, Kenneth W.	312/223.3
*	K	US-5,044,284	09-1991	Gross, Milton	108/10
*	L	US-4,706,920	11-1987	Ojima et al.	248/371
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	Ø					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	C						
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	х						

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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